

ASNT STANDARD

2016 EDITION

**TOPICAL OUTLINES FOR
QUALIFICATION OF
NONDESTRUCTIVE TESTING
PERSONNEL**



The American Society for Nondestructive Testing, Inc.
ASNT...Creating a Safer World!®

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ASNT Mission Statement:
ASNT exists to create a safer world by promoting the profession and technologies of nondestructive testing.

American National Standard
ASNT Standard Topical Outlines for
Qualification of Nondestructive Testing Personnel

Secretariat

The American Society for Nondestructive Testing, Inc.

Approved October 26, 2015

American National Standards Institute

Abstract

This standard applies to personnel whose specific tasks or jobs require appropriate knowledge of the technical principles underlying non-destructive testing (NDT) methods for which they have responsibilities within the scope of their employment. These specific tasks or jobs include, but are not limited to, performing, specifying, reviewing, monitoring, supervising, and evaluating NDT work.

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FOREWORD

(This foreword is not part of American National Standard CP-105-2011.)

An essential element in the effectiveness of nondestructive testing (NDT) is the qualification of the personnel who are responsible for and who perform nondestructive testing. Formal training is an important and necessary element in acquiring the skills necessary to effectively perform nondestructive tests.

The American Society for Nondestructive Testing, Inc. (ASNT) has, therefore, undertaken the preparation and publication of this standard, which specifies the body of knowledge to be used as part of a training program qualifying and certifying NDT personnel.

ASNT CP-105: ASNT Standard Topical Outlines for Qualification of Nondestructive Testing Personnel was initially processed and approved for submittal to the American National Standards Institute (ANSI) by the ASNT Standards Development Committee. This revision was processed by the ASNT Standards Development Committee. Committee approval of the standard does not necessarily imply that all committee members voted for its approval. At the time it approved this standard, the Standards Development Committee had the following members:

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